

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/084,239	JILINSKAIA ET AL.	
		Examiner	Art Unit	
		Carolyn M. Bleck	3626	Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,341,265 B1	01-2002	Provost et al.	705/4
*	B	US-6,343,271 B1	01-2002	Peterson et al.	705/4
*	C	US-6,879,959 B1	04-2005	Chapman et al.	705/2
*	D	US-6,636,862 B2	10-2003	Lundahl et al.	707/101
*	E	US-5,970,463 A	10-1999	Cave et al.	705/3
*	F	US-6,044,351 A	03-2000	Jones, Annie M. W.	705/2
*	G	US-5,778,345	07-1998	McCartney, Michael J.	705/2
*	H	US-5,615,109	03-1997	Eder, Jeff	705/8
*	I	US-6,061,657 A	05-2000	Whiting-O'Keefe, Quinn	705/2
*	J	US-5,018,067	05-1991	Mohlenbrock et al.	600/300
*	K	US-5,557,514	09-1996	Seare et al.	705/2
*	L	US-6,138,102	10-2000	Hinckley, Jr., Richard A.	705/36R
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Atrostic, B. K. (1994). A multiple imputation approach to microsimulation. Proceedings of the Survey Research Methods Section of the American Statistical Association, 529-534. pdf.
	V	Binder, D.A. and Sun, W. (1996). Frequency valid multiple imputation for surveys with a complex design. Proceedings of the Survey Research Methods Section of the American Statistical Association, 281-286
	W	Johnson, William, Yuichi Kitamura, and Derek Neal, Evaluating a Simple Method for Estimating Black-White Gaps in Median Wages, The American Economic Review, Vol. 90, No. 2, Papers and Proceedings of the One Hundred Twelfth Annual Meeting of the American Economic Association, (May 2000), pp. 339-343
	X	Software for multiple imputation website, revised June 12, 1999, accessed at www.stat.psu.edu/~jls/misoftwa.html

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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		Examiner Carolyn M. Bleck	Art Unit 3626	Page 2 of 2

U.S. PATENT DOCUMENTS

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	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Barcena, Maria Jesus, Fernando Tusell, Multivariate Data Imputation using Trees, 2000
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.